

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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In re application of: Mieher, et al.

Attorney Docket No.: KLA1P117X1A/  
P1151 CIP1

Application No.: 10/785,396

Examiner: Gordon J. Stock Jr.

Filed: February 23, 2004

Group: 2877

Title: APPARATUS AND METHODS FOR  
DETECTING OVERLAY ERRORS USING  
SCATTEROMETRY

Confirmation No. : 6516

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I hereby certify that this correspondence is being transmitted electronically through EFS-WEB to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450 on September 13, 2007.

Signed: /Mia Mitchell-Haynes/  
Typed: Mia Mitchell-Haynes

**AMENDMENT B**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully submitted that the Examiner enters the following amendments in response to the Office Action dated 14 June 2007, a response to which is due 14 September 2007.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims that begin on page 3 of this paper.

**Remarks/Arguments** begin on page 9 of this paper.

**Replacement Sheets** for Figs. 2a~2f, 3b, 5a, 7, and 11d~11f are submitted herewith.